5th IEEE International Workshop on Silicon Debug and Diagnosis - SDD08

April 30th (4pm-7pm) – May 1st (8am-5pm) 2008
San Diego, California, USA

Held in conjunction with the IEEE VLSI Test Symposium 2008

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Call for Papers

Scope and Mission

Troubleshooting how and why systems and circuits fail is important and is rapidly growing in industry significance. Debug and diagnosis may be needed for yield improvement, process monitoring, correcting the design function, failure mode learning for R&D, or just getting a working first prototype. This detective work can however become very tricky. Sources of difficulty include circuit and system complexity, packaging, limited physical access, shortened product creation cycle and time-to-market, the traditional focus on only pass/fail testing and missing tool and equipment capabilities. New and efficient solutions for debug and diagnosis will have a much needed and highly visible impact on productivity.

SDD08 will be held in San Diego, California, USA. It is the fifth in a series of highly successful technical workshops. Its mission and objective is to consider all issues related to debug and diagnosis of systems and circuits – from prototype bring-up to volume production.

The topics of interest include, but are not limited to, the following:

Debug Techniques and Methodologies
Design and Synthesis for Debug
DFT Reuse for Debug and Diagnosis
Debug & Diagnosis Architectures
Tools
Debug Standardization
SDD vs. Yield & TTM
Case studies
Microprocessor, FPGA, IP, SOC Debug
Infrastructure IP for SDD
System Level Debug & Diagnosis
Manufacturing & Prototype Environment
Equipment Impact and Techniques
Cross-geography turn-on, debug & diagnosis issues
Digital/Analog Turn-on

Author Information

The workshop objective is to facilitate a valuable interactive information exchange. Contributions ranging from extended abstracts to full papers are acceptable for submission. Proposals that describe open issues, industry/technology needs or opinions are also welcome.

- Length Guideline: 1 to 8 pages.
- Submissions due: March 7th
- Acceptance Notification: March 21st
- Final papers for inclusion into informal proceedings: April 1st

Proposals for discussion panels and other special sessions are also invited. Please submit a one page abstract for these to the web site or contact the Program Chair or Special Sessions Chair

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SDD08 is sponsored by the IEEE Computer Society Test Technology Technical Council.

For more information on SDD08, visit the website at: http://www.sdd-online.org